



SEMiX® 33c

## Trench IGBT Modules

## SEMiX223GD12E4c

## Features

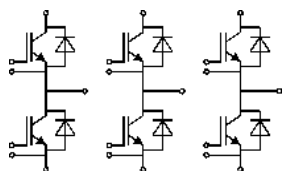
- Homogeneous Si
- Trench = Trenchgate technology
- $V_{CE(sat)}$  with positive temperature coefficient
- High short circuit capability
- UL recognized, file no. E63532

## Typical Applications\*

- AC inverter drives
- UPS
- Electronic Welding

## Remarks

- Case temperature limited to  $T_C=125^\circ\text{C}$  max.
- Product reliability results are valid for  $T_J=150^\circ\text{C}$



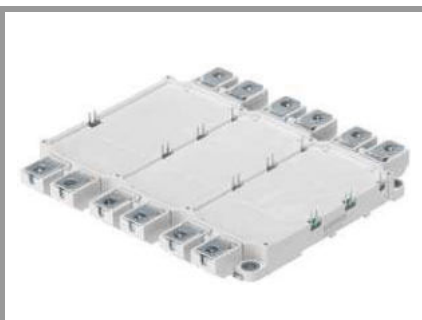
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## Absolute Maximum Ratings

| Symbol              | Conditions                                                                     |                         | Values      | Unit |
|---------------------|--------------------------------------------------------------------------------|-------------------------|-------------|------|
| IGBT                |                                                                                |                         |             |      |
| V <sub>CES</sub>    | T <sub>j</sub> = 25 °C                                                         |                         | 1200        | V    |
| I <sub>C</sub>      | T <sub>j</sub> = 175 °C                                                        | T <sub>c</sub> = 25 °C  | 333         | A    |
|                     |                                                                                | T <sub>c</sub> = 80 °C  | 256         | A    |
| I <sub>Cnom</sub>   |                                                                                |                         | 225         | A    |
| I <sub>CRM</sub>    | I <sub>CRM</sub> = 3xI <sub>Cnom</sub>                                         |                         | 675         | A    |
| V <sub>GES</sub>    |                                                                                |                         | -20 ... 20  | V    |
| t <sub>psc</sub>    | V <sub>CC</sub> = 800 V<br>V <sub>GE</sub> ≤ 20 V<br>V <sub>CES</sub> ≤ 1200 V | T <sub>j</sub> = 150 °C | 10          | μs   |
| T <sub>j</sub>      |                                                                                |                         | -40 ... 175 | °C   |
| Inverse diode       |                                                                                |                         |             |      |
| I <sub>F</sub>      | T <sub>j</sub> = 175 °C                                                        | T <sub>c</sub> = 25 °C  | 270         | A    |
|                     |                                                                                | T <sub>c</sub> = 80 °C  | 202         | A    |
| I <sub>Fnom</sub>   |                                                                                |                         | 225         | A    |
| I <sub>FRM</sub>    | I <sub>FRM</sub> = 3xI <sub>Fnom</sub>                                         |                         | 675         | A    |
| I <sub>FSM</sub>    | t <sub>p</sub> = 10 ms, sin 180°, T <sub>j</sub> = 25 °C                       |                         | 1161        | A    |
| T <sub>j</sub>      |                                                                                |                         | -40 ... 175 | °C   |
| Module              |                                                                                |                         |             |      |
| I <sub>t(RMS)</sub> | T <sub>terminal</sub> = 80 °C                                                  |                         | 600         | A    |
| T <sub>stg</sub>    |                                                                                |                         | -40 ... 125 | °C   |
| V <sub>isol</sub>   | AC sinus 50Hz, t = 1 min                                                       |                         | 4000        | V    |

## Characteristics

| Symbol        | Conditions                                                                            | min.                      | typ. | max.  | Unit             |
|---------------|---------------------------------------------------------------------------------------|---------------------------|------|-------|------------------|
| <b>IGBT</b>   |                                                                                       |                           |      |       |                  |
| $V_{CE(sat)}$ | $I_C = 225\text{ A}$<br>$V_{GE} = 15\text{ V}$<br>chipelevel                          | $T_J = 25^\circ\text{C}$  | 1.85 | 2.10  | V                |
|               |                                                                                       | $T_J = 150^\circ\text{C}$ | 2.3  | 2.45  | V                |
| $V_{CE0}$     | chipelevel                                                                            | $T_J = 25^\circ\text{C}$  | 0.8  | 0.9   | V                |
|               |                                                                                       | $T_J = 150^\circ\text{C}$ | 0.7  | 0.8   | V                |
| $r_{CE}$      | $V_{GE} = 15\text{ V}$<br>chipelevel                                                  | $T_J = 25^\circ\text{C}$  | 4.7  | 5.3   | $\text{m}\Omega$ |
|               |                                                                                       | $T_J = 150^\circ\text{C}$ | 6.9  | 7.3   | $\text{m}\Omega$ |
| $V_{GE(th)}$  | $V_{GE}=V_{CE}, I_C = 9\text{ mA}$                                                    | 5                         | 5.8  | 6.5   | V                |
| $I_{CES}$     | $V_{GE} = 0\text{ V}$<br>$V_{CE} = 1200\text{ V}$                                     | $T_J = 25^\circ\text{C}$  |      | 3.0   | mA               |
|               |                                                                                       | $T_J = 150^\circ\text{C}$ |      |       | mA               |
| $C_{ies}$     | $V_{CE} = 25\text{ V}$<br>$V_{GE} = 0\text{ V}$                                       | $f = 1\text{ MHz}$        | 13.2 |       | nF               |
| $C_{oes}$     |                                                                                       | $f = 1\text{ MHz}$        | 0.87 |       | nF               |
| $C_{res}$     |                                                                                       | $f = 1\text{ MHz}$        | 0.71 |       | nF               |
| $Q_G$         | $V_{GE} = -8\text{ V...} + 15\text{ V}$                                               |                           | 1275 |       | nC               |
| $R_{Gint}$    | $T_J = 25^\circ\text{C}$                                                              |                           | 3.33 |       | $\Omega$         |
| $t_{d(on)}$   | $V_{CC} = 600\text{ V}$<br>$I_C = 225\text{ A}$                                       | $T_J = 150^\circ\text{C}$ | 213  |       | ns               |
| $t_r$         | $V_{GE} = \pm 15\text{ V}$                                                            | $T_J = 150^\circ\text{C}$ | 60   |       | ns               |
| $E_{on}$      | $R_{G on} = 1.5\text{ }\Omega$                                                        | $T_J = 150^\circ\text{C}$ | 22   |       | mJ               |
| $t_{d(off)}$  | $R_{G off} = 1.5\text{ }\Omega$                                                       | $T_J = 150^\circ\text{C}$ | 535  |       | ns               |
| $t_f$         | $di/dt_{on} = 3630\text{ A}/\mu\text{s}$<br>$di/dt_{off} = 2235\text{ A}/\mu\text{s}$ | $T_J = 150^\circ\text{C}$ | 113  |       | ns               |
| $E_{off}$     |                                                                                       | $T_J = 150^\circ\text{C}$ | 31.4 |       | mJ               |
| $R_{th(j-c)}$ | per IGBT                                                                              |                           |      | 0.135 | K/W              |



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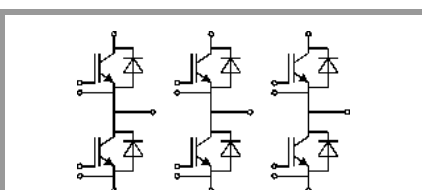
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#### Remarks

- Case temperature limited to  $T_C=125^\circ\text{C}$  max.
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| Characteristics                  |                                                                                               |                         |             |      |      |      |
|----------------------------------|-----------------------------------------------------------------------------------------------|-------------------------|-------------|------|------|------|
| Symbol                           | Conditions                                                                                    |                         | min.        | typ. | max. | Unit |
| Inverse diode                    |                                                                                               |                         |             |      |      |      |
| V <sub>F</sub> = V <sub>EC</sub> | I <sub>F</sub> = 225 A                                                                        | T <sub>j</sub> = 25 °C  |             | 2.2  | 2.49 | V    |
|                                  | V <sub>GE</sub> = 0 V<br>chiplevel                                                            | T <sub>j</sub> = 150 °C |             | 2.1  | 2.4  | V    |
| V <sub>F0</sub>                  | chiplevel                                                                                     | T <sub>j</sub> = 25 °C  | 1.1         | 1.3  | 1.5  | V    |
|                                  |                                                                                               | T <sub>j</sub> = 150 °C | 0.7         | 0.9  | 1.1  | V    |
| r <sub>F</sub>                   | chiplevel                                                                                     | T <sub>j</sub> = 25 °C  | 3.6         | 3.9  | 4.4  | mΩ   |
|                                  |                                                                                               | T <sub>j</sub> = 150 °C | 4.7         | 5.4  | 5.9  | mΩ   |
| I <sub>RRM</sub>                 | I <sub>F</sub> = 225 A                                                                        | T <sub>j</sub> = 150 °C | 210         |      |      | A    |
| Q <sub>rr</sub>                  | di/dt <sub>off</sub> = 3900 A/μs                                                              | T <sub>j</sub> = 150 °C | 37          |      |      | μC   |
| E <sub>rr</sub>                  | V <sub>GE</sub> = -15 V<br>V <sub>CC</sub> = 600 V                                            | T <sub>j</sub> = 150 °C | 17.2        |      |      | mJ   |
| R <sub>th(j-c)</sub>             | per diode                                                                                     |                         |             |      | 0.22 | K/W  |
| Module                           |                                                                                               |                         |             |      |      |      |
| L <sub>CE</sub>                  |                                                                                               |                         | 20          |      |      | nH   |
| R <sub>CC'+EE'</sub>             | res., terminal-chip                                                                           | T <sub>C</sub> = 25 °C  | 0.7         |      |      | mΩ   |
|                                  |                                                                                               | T <sub>C</sub> = 125 °C | 1           |      |      | mΩ   |
| R <sub>th(c-s)</sub>             | per module                                                                                    |                         | 0.014       |      |      | K/W  |
| M <sub>s</sub>                   | to heat sink (M5)                                                                             |                         | 3           |      | 5    | Nm   |
| M <sub>t</sub>                   |                                                                                               | to terminals (M6)       | 2.5         |      | 5    | Nm   |
|                                  |                                                                                               |                         |             |      |      | Nm   |
| w                                |                                                                                               |                         |             |      | 900  | g    |
| Temperature Sensor               |                                                                                               |                         |             |      |      |      |
| R <sub>100</sub>                 | T <sub>c</sub> =100°C (R <sub>25</sub> =5 kΩ)                                                 |                         | 493 ± 5%    |      |      | Ω    |
| B <sub>100/125</sub>             | R <sub>(T)</sub> =R <sub>100</sub> exp[B <sub>100/125</sub> (1/T-1/T <sub>100</sub> )]; T[K]; |                         | 3550<br>±2% |      |      | K    |



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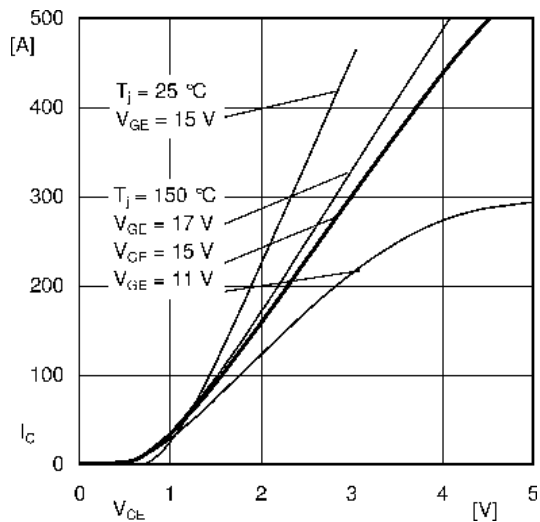
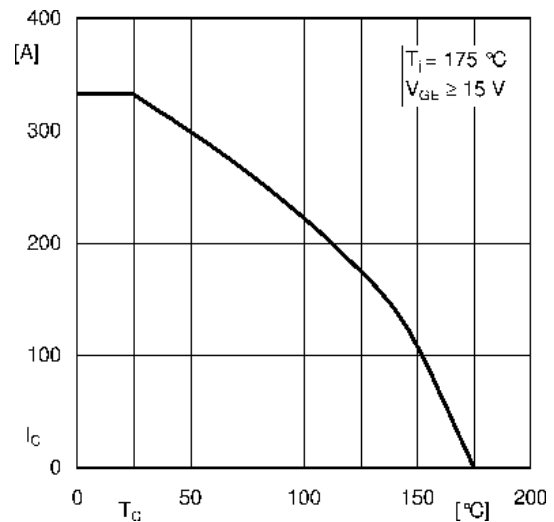
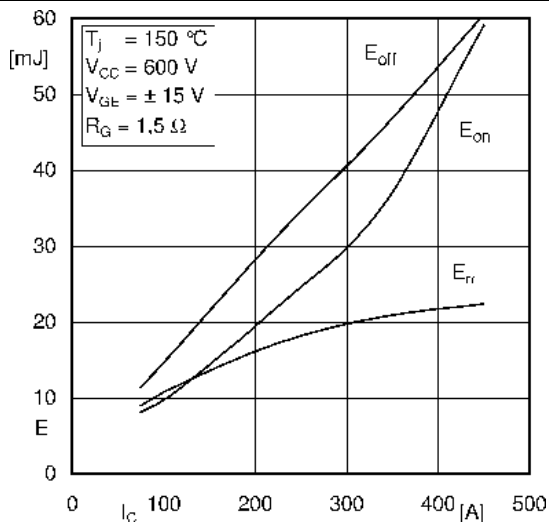
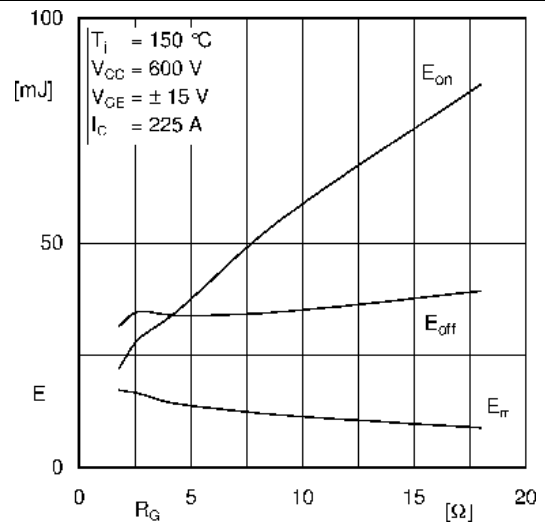
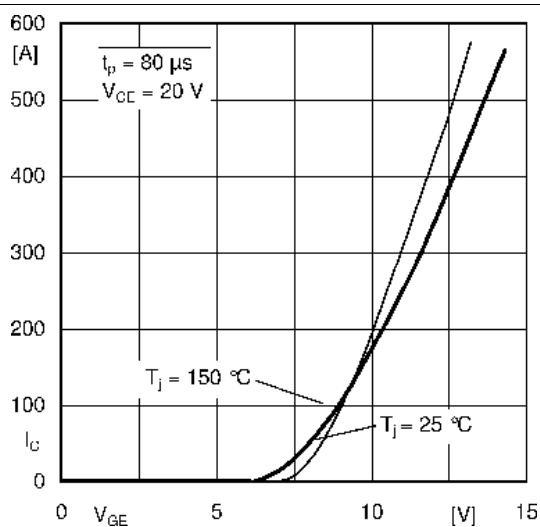
Fig. 1: Typ. output characteristic, inclusive  $R_{CC} + EE'$ Fig. 2: Rated current vs. temperature  $I_C = f(T_C)$ Fig. 3: Typ. turn-on /-off energy =  $f(I_C)$ Fig. 4: Typ. turn-on /-off energy =  $f(R_G)$ 

Fig. 5: Typ. transfer characteristic

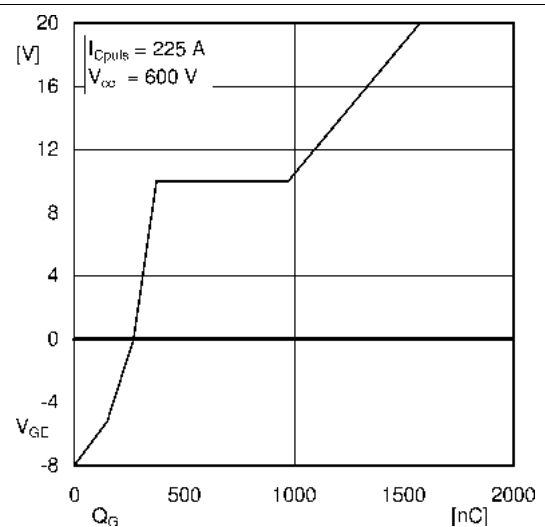


Fig. 6: Typ. gate charge characteristic

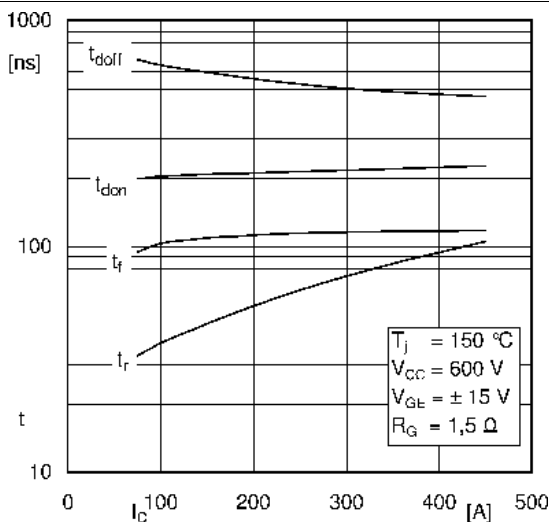


Fig. 7: Typ. switching times vs.  $I_C$

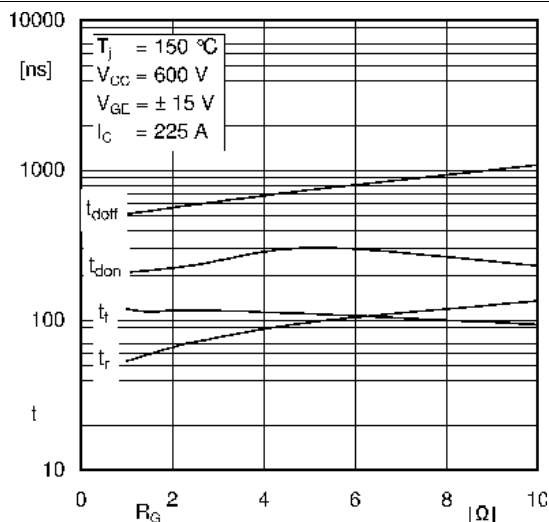


Fig. 8: Typ. switching times vs. gate resistor  $R_G$

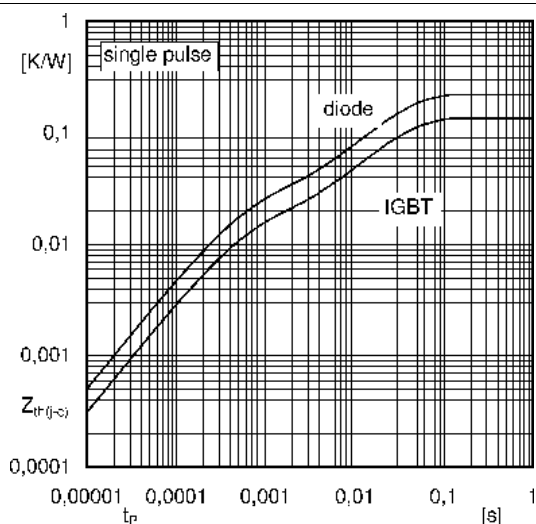


Fig. 9: Typ. transient thermal impedance

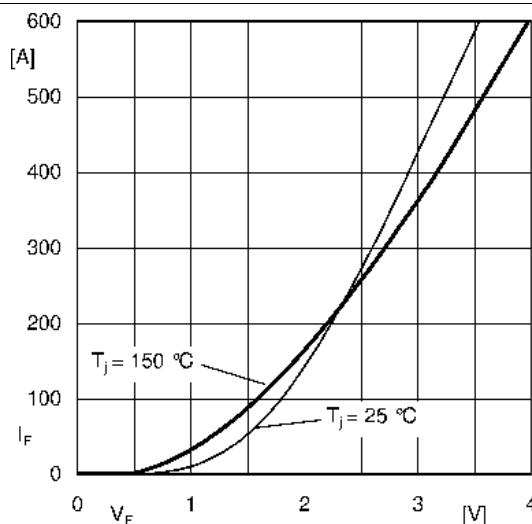


Fig. 10: Typ. CAL diode forward charact., incl.  $R_{CC'+EE'}$

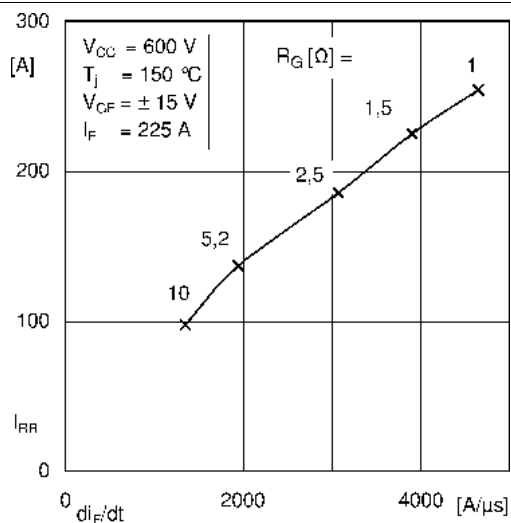


Fig. 11: Typ. CAL diode peak reverse recovery current

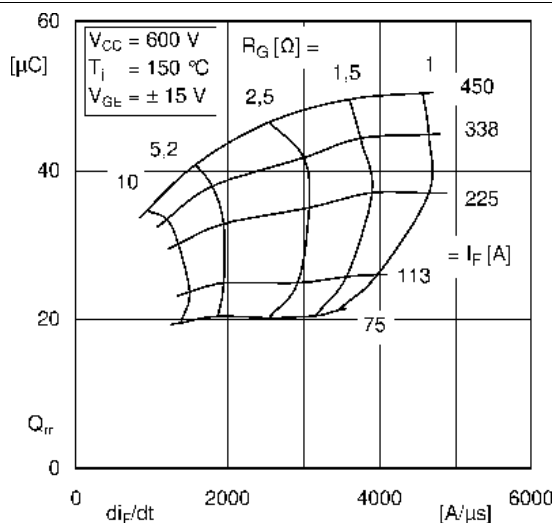


Fig. 12: Typ. CAL diode recovery charge



\* The specifications of our components may not be considered as an assurance of component characteristics. Components have to be tested for the respective application. Adjustments may be necessary. The use of SEMIKRON products in life support appliances and systems is subject to prior specification and written approval by SEMIKRON. We therefore strongly recommend prior consultation of our staff.